Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/685,453	CHUNG, DAVID B.	
Examiner	Art Unit	
HOAN C. NGUYEN	2871	

SEARCHED				
Class	Subclass	Date	Examiner	
349	2	3/23/2006	CHN	
		•		
_				
•				
		· .		
			· .	

· INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		_			
		<u> </u>			
	<u></u>				
· · ·	-				
	·				

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
East search in US-PGPUB, USPAT, EPO, JPO	3/23/2006	CHN
		,
•		